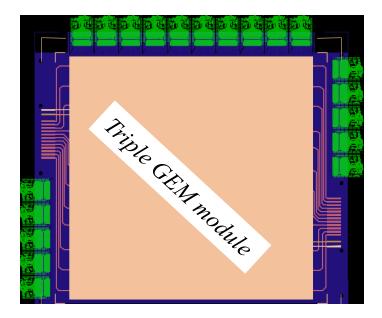
Update on SBS Back Tracker GEM @ UVa

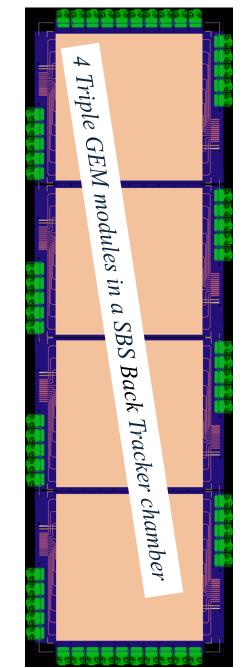
K. Gnanvo, N. Liyanage, V Nelyubin, K. Saenboonruang, Seth Saher, Nikolai Pillip (visiting from Univ. Tel Aviv, Israel)

- Preliminary tests and results
- Improvements for the next two prototypes

Design of 50 ×50 cm² Back Tracker GEM

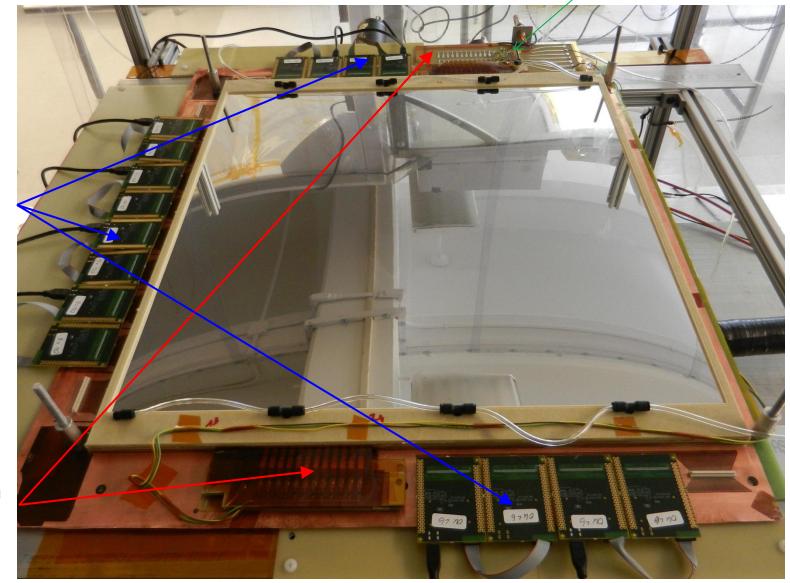


- Module of $50 \times 50 \text{cm}^2$ to replace the $40 \times 50 \text{cm}^2$
 - 32 modules to be built instead of 40 for the 8 SBS Back Tracker
 GEM chambers → Reduce the overall cost and dead area
- No protective resistors on the GEM foils \rightarrow external resistor board
 - Individual HV test of all the sectors at different stages of the assembly and safer to operate during the assembly
- Wider GEM frames and readout honeycomb support along x-axis
 - 30 mm instead of 8 mm, alignment holes away from active area
 - Room for strips connectors and GEM HV sectors electrodes
 - Holes for mechanical positioning of the chamber on the frame



SBS Back Tracker GEM module Proto 1

HV divider

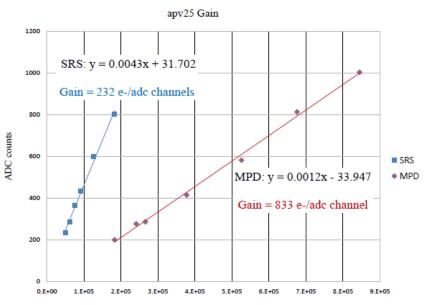


Apv25-SRS FE cards

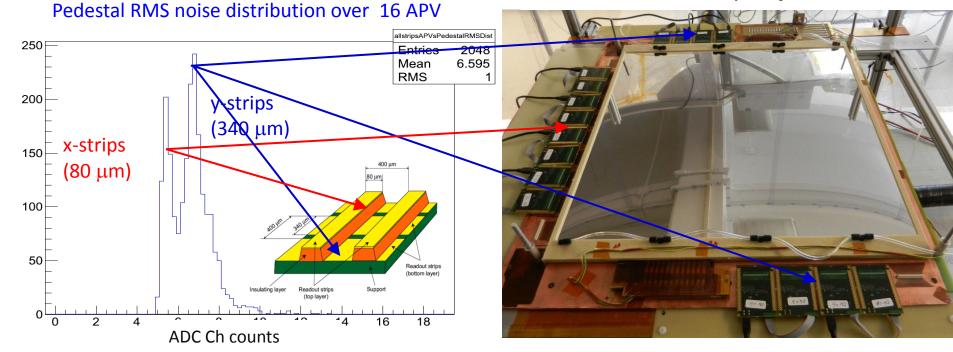
Spark protection resistors Board

Pedestal RMS noise

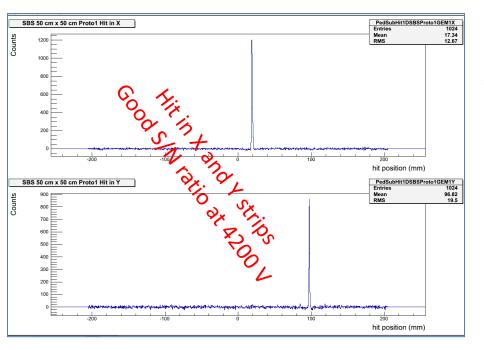
- For 50 × 50 cm2 COMPASS-like readout, typical rms after common mode correction of the baseline is on average of 6-7 adc counts for apv25-SRS
 - @ 230 e-/adc → ~ 1200 to 1500 ENC
 - a cut at 5 sigma for zero suppression \rightarrow ~ 6000 e-



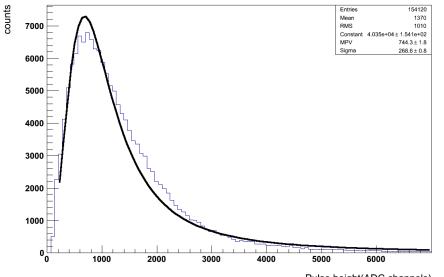
number of injected charges



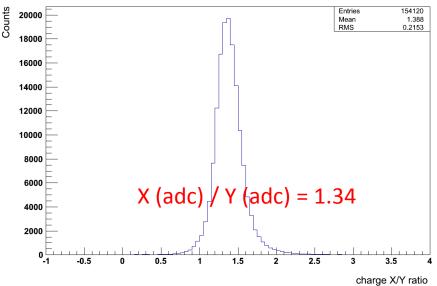
Preliminary test with cosmic data



Cluster ADC sum distribution

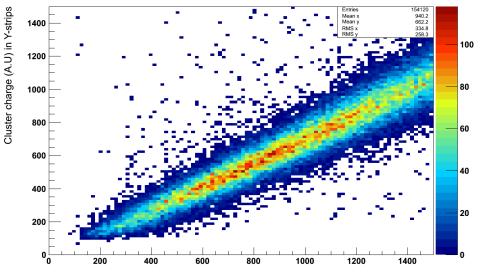


Pulse height(ADC channels)



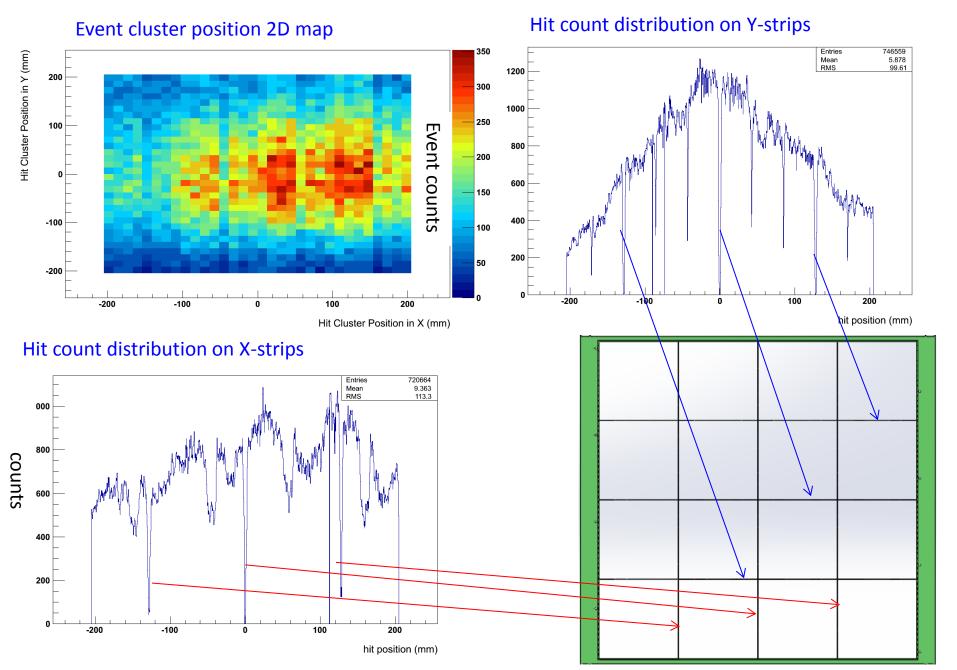
X-Y strips charge sharing ratio

X/Y strips charge sharing correlation



Cluster charge (A II) in X-strins

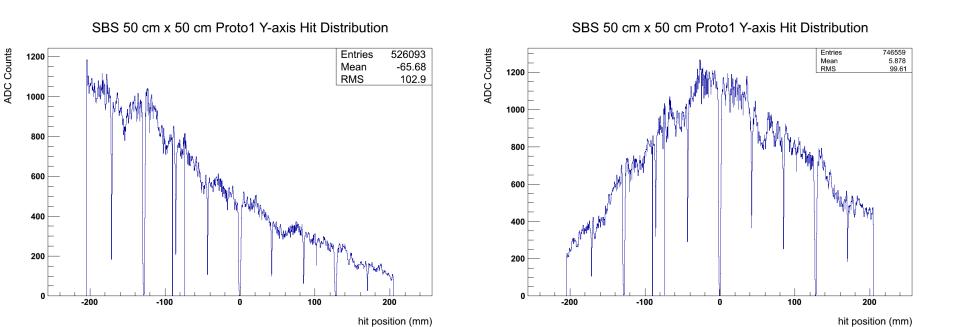
Preliminary test with cosmic data



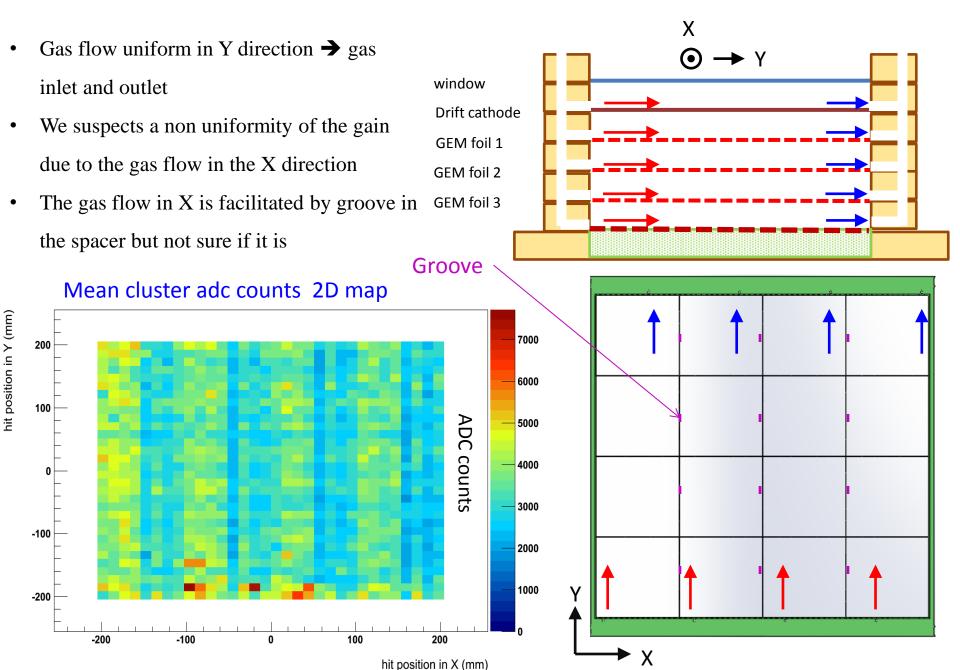
Non uniformity from the scintillator counters

We use 2 set of 3 scintillators paddle in coincidence for the trigger on cosmic

Changing the arrangement of the paddles in the set up lead to a big changes in the hit distribution profiles Main source of the non uniformity here

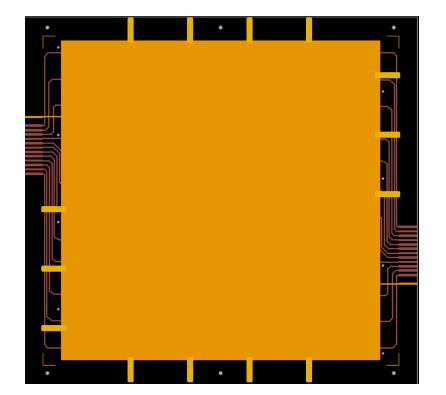


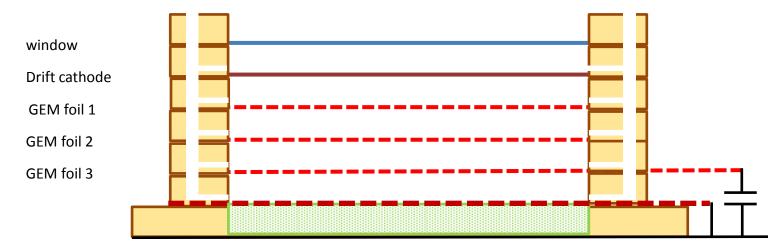
Gain (non) uniformity of the chamber



Suggestions for improvements for the next two prototypes

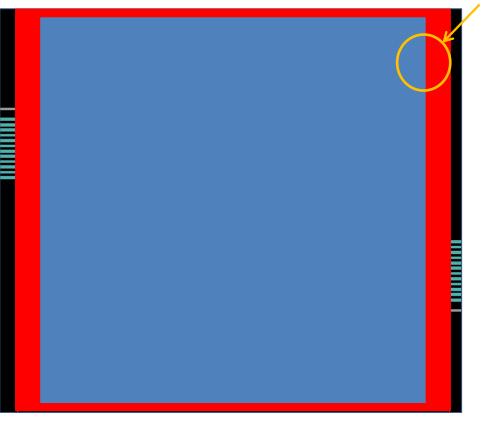
Faraday cage shielding using GEM foil common electrode





Safe area around the frame on GEM foil

Current design



Solution

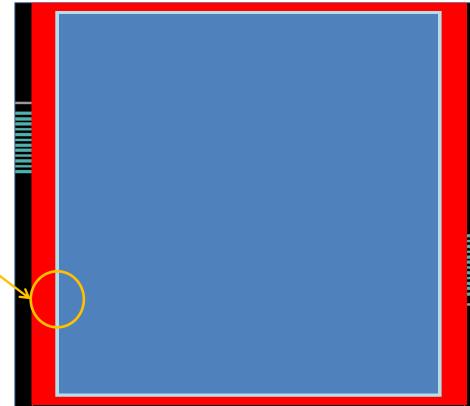
 We propose 1 mm clearance between the frame (inner part) and the GEM foil active area → Kapton foil with no holes

Problem

- No space between the GEM Frame (inner part)and the GEM foil active area
- Glue can leak onto the foil during assembly \rightarrow

Sector will spark at high rate \rightarrow but Can be cured

Proposed modification

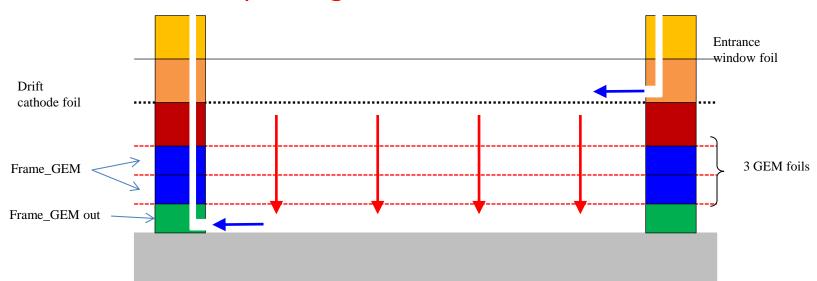


New Gas distribution scheme for the chamber

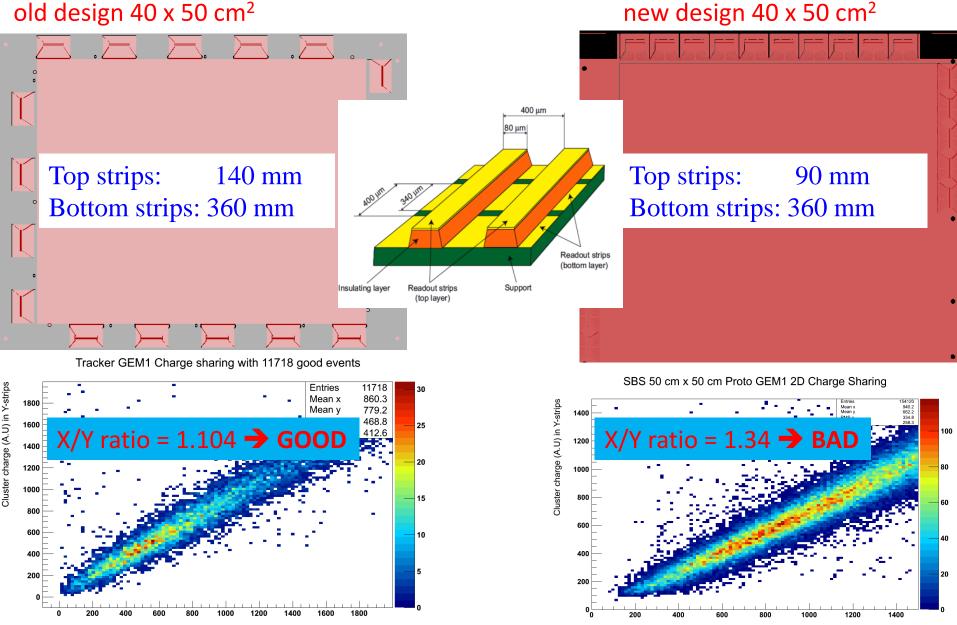
Current gas distribution scheme



Proposed gas distribution scheme



Charge sharing and 2D readout strips width



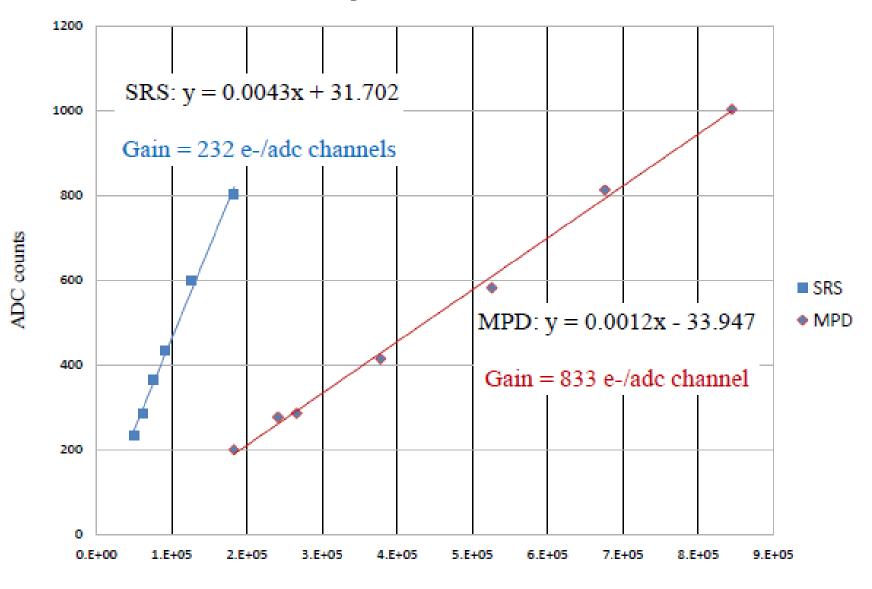
Cluster charge (A.U) in X-strips

Cluster charge (A.U) in X-strips

BACKUP

APV25 Gain: MPD vs SRS

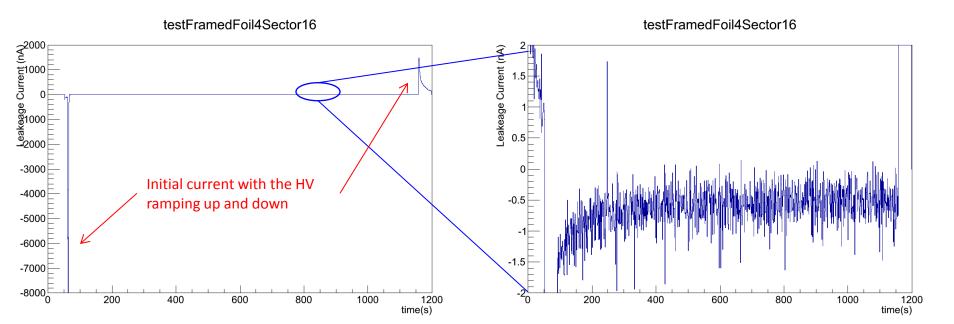
apv25 Gain



number of injected charges

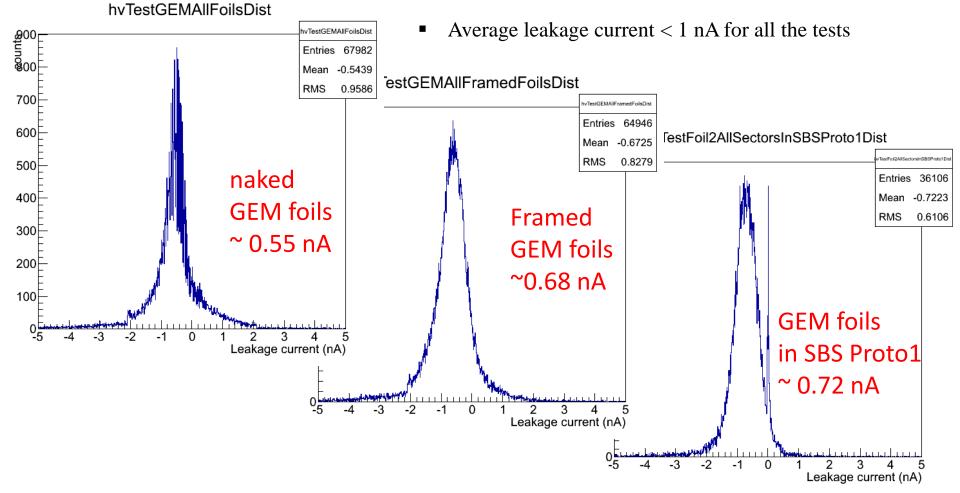
HV test of the GEM sectors

- We use an Iseg EHS 6 kV HV module in a Wiener crate, HV controlled through an internet protocol.
- Fast ramp up mode at a rate of 1200 V/s.
- The leakage current in the GEM is measured using a Keithley 6487 picoammeter, at sampling rate of 120 ms with a Labview interface and saved in txt file.
- HV GEM sector ~ 2 nF and with a resistance the HV module is ~ 50 MΩ, (once the voltage is achieved this resistance is shunted automatically within the supply).
- HV of 550 V, the initial current is a couple of μA , then quickly drops and stabilizes to less 1 nA leakage.
- We leave the HV for about 2 min and if no spark \rightarrow sector is good



HV test of the GEM sectors

- Distribution of leakage current over all the 72 sectors (24 sectors per GEM foil and 3 foils per chamber)
- HV Test is performed at 550V in N2 for naked, framed foils and in chamber foils



Recovering of a bad HV sector

Excess of glue leaked onto the sector during assembly \rightarrow sector recovered after curing on N2 or at 50 degree

